M agnetic Field Induced Spin Polarization of AlAs Two-dim ensional Electrons

E.P.De Poortere, E. Tutuc, Y.P. Shkolnikov, K. Vakili, and M. Shayegan Department of Electrical Engineering, Princeton University, Princeton, New Jersey 08544 (Dated: March 22, 2024)

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The ground state properties of dilute 2D carrier system s are still under close scrutiny, and several issues, such as the existence of a metal-insulator transition and the occurrence of a ferrom agnetic instability at zero m agnetic elds, remain largely unresolved. At the lowest densities (n), calculations predict that 2D electrons settle into a W igner crystal [1], while at the highest n, a param agnetic Ferm i liquid m odelm ost likely describes the ground state of the 2D electron system (2DES). At intermediate densities, a Stoner transition to a fully spin polarized ground state may take place [1, 2, 3, 4, 5], but experim ental evidence for such a phase has been scant so far. A sem i-direct m ethod used to probe this ferrom agnetic state involves measuring the product jg jm in the 2D electron system at various densities. A diverging ig in as n approaches a critical density, would then imply that the system spontaneously polarizes at lowern. A coordingly, several groups have recently studied the density dependence of ig in in dilute 2D carrier systems, but have not yet reached an agreem ent. Som e of these groups have reported an increasing jg jm as n decreases in Si MOSFETs [6, 7, 8, 9, 10]. Furtherm ore, scaling argum ents based on in-plane m agnetoresistance of electrons in the same system [9, 10] suggest that jg jm diverges at a nite density, hinting at a possible Stoner instability. On the other hand, measurements of jg jm in 2D carrier systems in GaAs [11, 12, 13] point to the contrary. Direct m easurements of the magnetization of Si2D electrons also o er no evidence for a ferrom agnetic ground state [14].

In an attempt to resolve these discrepancies, we have performed experiments in a new system, 2D electrons in AlAs, in which the electrof disorder is very much reduced: we have recently obtained AlAs samples with electron mobilities as high as 30 m 2 /Vs [15]. For similar r_s , defined as the ratio of average interparticle separation to the electroe Bohr radius, mobilities in AlAs are roughly an order of magnitude larger than those in Si, and a factor 2 lower than in GaAs. We not that it in in AlAs 2D electrons is approximately independent of density for

the measured range 0.5 < n < 5.9 10^{11} cm 2 . Our results imply that the ground state of the AlAs 2DES remains unpolarized at all measured densities, a conclusion in agreement with transport experiments in GaAs and with magnetization measurements in Si [14].

The electronic band structure of A IAs is rem in iscent of that of Si: conduction electrons in A IAs, located at the X-point of the Brillouin zone, have an isotropic e ective m ass $(m_1 = 1.0, m_t = 0.2)$ almost identical to that of Si, and a band g-factor equal to 2, as in Si [16]. In 2D however, properties of Siand A IA selectrons are di erent: A lAs (100) 2D electrons in quantum wells wider than 45 A [17, 18] occupy X-point valleys with principal axes parallel to the plane of the 2D ES, so that their cyclotron e ective mass is $m_b = (m_1 m_t)^{1=2} = 0.46$ [19], while in Si (100), out-of-plane valleys are occupied, and $m_b = m_t =$ 02 (e ective m asses are given in units of the free electron mass). Strain induced by lattice-mismatch between the A IAs quantum well and A IG aAs barriers is responsible for increasing the energy of the out-of-plane valleys in A lAs relative the energy of the in-plane valleys, so that for wide A lAs quantum wells, such as those used in our study, in-plane valleys are occupied. In SiM O SFET sand in narrow A IAs quantum wells, on the other hand, outof-plane plane valleys are populated due to the higher e ective mass in the growth direction.

Results for three samples (A-C) are presented here. These were grown by molecular beam epitaxy atop a GaAs (411)B substrate for sample A (M 393 IV -D2), and GaAs (100) substrates for samples B (M 420-D3) and C (M 415-J2). The layer structures for these samples are composed of a 150 A (samples A and C) or a 120 A-wide (sample B) AlAs quantum well, sandwiched between Al_xGa_{1x} As barriers, with 0.25 < x < 0.4, and modulation doped with Si. We patterned all samples in a Hallbar geometry for transport measurements in magnetic elds up to 18 T, which were conducted in a 3 He cryostat with a base temperature of T = 300 mK, and in a dilution refrigerator for T down to 30 mK. Samples were mounted on a single-axis rotator stage, which al-

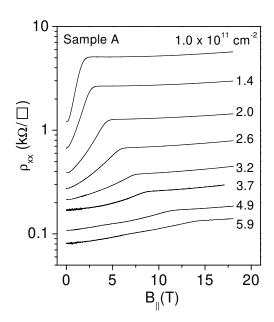


FIG. 1: In-plane m agnetoresistance of A IAs 2D electrons for dierent carrier densities in sample A at T $^\prime$ 30 m K .M agnetoresistance increases strongly at low elds, and saturates or increases m ore slowly at higher elds, when the 2DES is fully polarized.

lowed us to tune the angle between the magnetic eld direction and the plane of the 2D electron system . After illum ination, carrier density was varied with the help of both front—and back—gates, and was determined from Shubnikov—de H aas oscillations measured in a perpendicular magnetic eld. In sample A, electron mobility at T = 30 m K ranged from = $5.6 \, \text{m}^2/\text{V} \, \text{s}$ at n = $1.2 \, 10^{11} \, \text{cm}^2$ to = $14 \, \text{m}^2/\text{V} \, \text{s}$ at n = $5.9 \, 10^{11} \, \text{cm}^2$.

In-plane m agnetoresistance data ($_{\mbox{\scriptsize xx}})$ for sam ple A are plotted in Fig. 1 for several carrier densities. As in SiMOSFETs, the resistivity shows a strong increase with B $_{\rm ii}$ at low elds, while it rises much more slowly beyond a crossover $\ \, \text{eld} \,\, B_P$. Based on experimental [7, 11, 12, 20] and theoretical [21] work, it is believed that at B_P the 2D ES undergoes a transition from a partially spin-polarized state to a fully spin-polarized state. For one of the traces shown (n = $2.6 10^{11}$ cm²), using am ethod reported previously [11], we veri ed that above B_P the system indeed becomes spin-polarized. We note that Pudalov et al. [22] have reported that the crossover eld in SiM O SFETs is sample dependent, and conclude that BP does not re ect complete spin polarization of the 2DES. As our results, in contrast, are reproduced in several samples, we follow the assumption that B_P does re ect full spin polarization of the 2DES. At B = B_P , the Fermi energy of the system is equal to its Zeem an energy, which gives the following relationship between Bp and jg jm:

$$B_{P} = \frac{n}{jg jm} \frac{2h}{e}; \qquad (1)$$

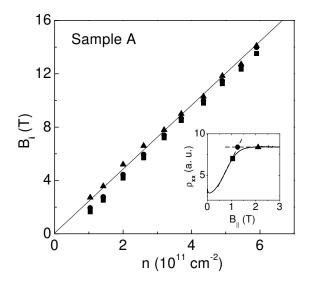


FIG. 2: $B_{\text{m in}}$, $B_{\text{m id}}$, $B_{\text{m ax}}$ elds vs. n for sample A (T '30 mK). Inset: Schematic de nition of B_{i} elds, indicated by squares, circles and triangles respectively. These elds de ne a range within which spin subband depopulation likely takes place.

valid for a single-valley 2DES [23]. From this equation, and know in gB_P , we can thus extract the product jg jn.

The crossover in magnetoresistance in Fig. 1 is not

perfectly sharp, but can be described empirically by tting straight lines to the low-and high-eld ranges of the trace (in a linear plot), and de ning two respective elds, $B_{m in}$ and $B_{m ax}$, at which xx deviates from these lines (see Fig. 2 inset). A deviation ratio of 1% is used for $B_{m in}$, while we use 0.1% for $B_{m ax}$ [24]. A sm aller deviation criterion is used for B $_{\text{m ax}}$ than for B $_{\text{m in}}$, because $_{\text{xx}}$ departs more abruptly from the straight line t around $B_{\,\text{m}\,\,\text{ax}}$. The two deviation points are m arked respectively by squares and triangles in the inset of Fig. 2. A third eld $(B_{m id})$, marked by a circle in Fig. 2, is de ned as the intersection between the two lines. For A IAs 2D electrons, full spin polarization likely takes place within the range $B_{\text{m in}}$, $B_{\text{m ax}}$], though we do not know the exact relationship between the actual polarization $eld B_P$ and the range lim its. In this paper we assum e, as is evidenced in GaAs 2D electrons [11] and holes [25], that B_P is the upper $eld B_{m ax}$. For completeness, we also provide here the range of values, $[B_{m \text{ in}}, B_{m \text{ ax}}]$, within which B_{P} is likely to lie. We note that our conclusion, namely, that jg jn does not increase as n decreases, does not depend

We plot in Fig. 2 the three \B_i " elds B_m in , B_m id , and B_m ax , obtained from the traces in Fig. 1, as a function of sam ple density. These values increase remarkably linearly with density, and a through the upper elds B_m ax appears to intercept the horizontal axis at a density small enough as to be identified with zero, within

on the choice of B_P within the range $[B_{m \text{ in}}, B_{m \text{ ax}}]$.

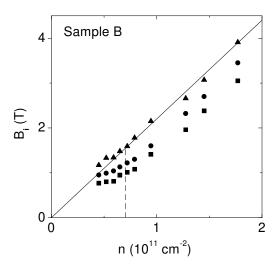


FIG.3: B $_{
m i}$ elds vs.n for sample B (T $^{\prime}$ 300 mK). The elds decrease linearly with decreasing n over most of the range, but tend to saturate at low n. The dashed line indicates the density at the apparent zero-eld m etal-insulator transition.

errorm argins. In Fig. 3, sim ilar data is plotted for sam ple B at T = 300 mK, for a lower density range. For n < 1 10^{11} cm 2 , the data points do not decrease linearly as n is low ered, but appear to extrapolate to a nite eld at zero density. To verify that this saturation does not result from the nite temperature of measurements, we record the B $_{
m i}$ elds for several tem peratures [Fig. 4 (a-c)]. For all m easured densities, the $\,$ elds $B_{m\,\,\mathrm{in}}\,$ and $B_{m id}$ are approximately independent of T for T $^{<}$ 300 m K [26]. In Fig. 4 (d) we also plot the tem perature dependence of R_{xx} (B $_{ii}$) for the lower two densities in sample A. As for GaAs electrons and holes [11, 12, 13, 25] and for Si electrons [7, 27], we observe a transition from metallic to insulating behavior near a nite eld B, lower than $B_{m \ in}$. We also note that the apparent zero- eld insulating-to-m etallic transition in A IA s 2D electrons occurs in sample B at $n = 0.7 ext{ } 10^{11} ext{ cm}^{2} ext{ } [28], indicated by$ a dashed line in Fig. 3, which corresponds approxim ately to the onset of B i saturation as n is lowered. A similar saturation for $n < n_c$ seems to also take place in other 2D systems, such as in GaAs holes [13] and in SiMOS-FETs [29]. The physics behind this phenomenon may be related to a disorder-induced broadening of the spin subbands, but certainly needs further theoretical and experim ental attention.

We conclude this paper by deriving the product jg jn from our magnetoresistance data, using Eq. 1. We assume that spin subband depopulation occurs at the eld B_{max} [11, 25], and plot in Fig. 5 the deduced jg jn for several A IAs samples (including samples A and B [30]), normalized to their band values using $g_b = 2.0$, and $m_b = 0.46$ and 0.41 for (100) and (411)B-oriented substrates respectively. The magnitude of the jg jn enhancement is approximately equal to 4, a value comparable to the

enhanced jg jm in GaAs and Si2D carrier systems for similar $r_{\rm s}$. Remarkably, we also observe that jg jm in AlAs is roughly independent of n for a wide range of densities.

Our results thus contrast with studies of spin polarization in SiM O SFETs, which not that jg jm increases at low densities [6, 7, 8, 9, 10]. A uthors in Refs. 9 and 10 obtain their conclusions after scaling the magnetoresistance with a single curve independent of B or T. We not that for A IAs 2D electrons, no linear mapping of B, $_{\rm xx}$ or $_{\rm xx}$ (= 1= $_{\rm xx}$) is able to generate such a scaling law. We thus rely solely on Eq.1 to obtain values for jg jm . Our data therefore do not point to a ferrom agnetic ground state at any nite density, which is consistent with the behavior of GaAs 2D electrons [11] and holes [12, 13, 25].

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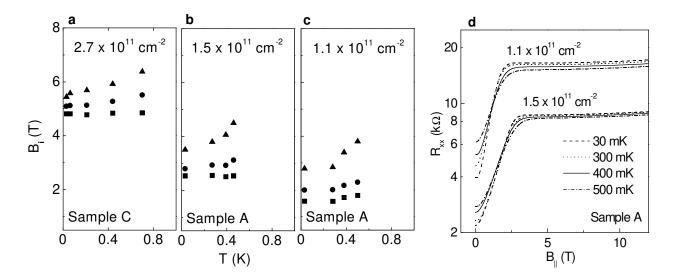


FIG. 4: (a-c) Temperature dependence of B_i elds (de ned in text) for three dierent densities. Data are shown for sample A in (b) and (c), and for sample C in (a). (d) T dependence of in-plane magnetoresistance of sample A.

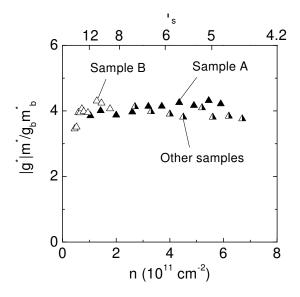


FIG. 5: Product (jg jm) of the e ective g-factor and e ective m ass in A A s 2D electrons, deduced from data plotted in F igs. 2 and 3, normalized to its band value. jg jm is remarkably constant over most of the density range.

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- can assum e single valley occupation. In Fig.1, a less pronounced $\$ in $_{\rm xx}$ can indeed be seen at B $_{\rm xx}$ for the highest density, and m ay be related to the depopulation of one of the valleys.
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- [30] Figure 5 also contains data from other 150 A -wide, (100) oriented, A IAs quantum wells.